Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/623,369	RYS ET AL.	
Examiner	Art Unit	
Vious With	2165	

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Class	Subclass	Date	Examiner		
707	1-10, 100- 104.1 200-206	3/6/2006	YW		
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SEARCH NO (INCLUDING SEARCH)
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inventor search (double patenting) uspto uspgpub epo jpo ibmtech derwent	3/6/2006	ΥW
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